

Special section on selected papers from the 2003 Chinese National Symposium on X-ray Diffraction

Late last year, I had an opportunity to visit China and to attend the 8th Chinese National Symposium on X-ray Diffraction held from October 29 to November 1 at GuanXi University, Nanning, China. The symposium was jointly organized by the Committee on X-ray Diffraction of Chinese Physical Society, the Committee on Powder Diffraction of Chinese Crystallographic Society, and Guangxi University. I learned from the symposium organizers that powder diffraction is a very popular analytical technique in China. There are about 2,000 X-ray powder diffractometers, 500 XRD scientists and 2,500–3,000 technicians in China. Most Chinese universities offer experimental courses in X-ray diffraction. The National Symposium on X-ray Diffraction is held every 3 years, and the National Conference on Crystallography every 4 years. There are 15 ICDD members, and about 16 Chinese scientists receive Grants-in-Aid from ICDD.

The 2003 Chinese National Symposium on X-ray Diffraction had about 150 participants (50% from universities, 32% government institutes, 10% X-ray equipment representatives, 5% industry, and 3% overseas guests). A significant number of the participants were female, and the ratio between female and male was 1:2. More than 60 technical pa-

pers on theoretical research, experimental techniques, structural determinations, and XRD applications were presented at the Symposium. I found that the qualities of many papers presented at the 2003 Symposium were good and the results were quite interesting. In order for the readers of *Powder Diffraction* to learn more about X-ray diffraction works in China, I asked the symposium organizers to encourage their speakers to prepare and submit papers for possible publication in *Powder Diffraction*. I am delighted that we are able to publish seven Chinese papers in a special section of the December 2004 issue of *Powder Diffraction*. I hope that our readers will enjoy reading these papers and can learn more about X-ray diffraction activities conducted by our colleagues in China. Finally, I want to thank Professors X.-L. Chen, S.-F. Lin, Y.-Y. Qiao, and X.-K. Yao of China for selecting and reviewing these papers. Special thanks also to Professor L.-M. Zeng, Local Chairman of the Symposium, for being an excellent host for my visit to China.

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